

SiC MOSFET Module

SKM260MB170SCH17

Features*

- Full Silicon Carbide (SiC) power module
- High reliability 2nd Generation SiC **MOSFETs**
- · Optimized for fast switching and lowest power losses
- External SiC Schottky Barrier Diode embedded
- Insulated copper baseplate using DBC technology (Direct Bonded Copper)
- Improved thermal performances with Aluminum Nitride (AIN) substrate
- UL recognized, file no. E63532

Typical Applications

- High frequency power supplies
- · AC inverters
- Traction APU
- EV Chargers
- · Industrial Test Systems

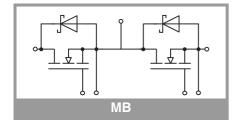
Remarks

- Case temperature limited to T_C = 125°C
- Recommended $T_{jop} = -40 \dots +150$ °C
- Gate-Source SURGE VOLTAGE $(t_{surge} < 300ns), V_{GS_surge} = -10V ... +26V$

Absolute Maximum Ratings						
Symbol	Conditions		Values	Unit		
MOSFET						
V_{DSS}	T _j = 25 °C		1700	V		
I _D	T _j = 175 °C	T _c = 25 °C	378	Α		
		T _c = 80 °C	301	Α		
I _{DM}	PW ≤ 10µs, Duty cycle ≤ 1%		980			
I _{DM,repetitive}			790	Α		
V_{GS}			-6 22	V		
T _j			-40 175	°C		

Absolute Maximum Ratings							
Symbol	Conditions		Values	Unit			
Inverse diode							
V_{RRM}	T _j = 25 °C		1700	V			
l _F	T _j = 175 °C	T _c = 25 °C	552	Α			
		T _c = 80 °C	428	Α			
I _{Fnom}			300	Α			
I _{FRM}			900	Α			
I _{FSM}	t_p = 10 ms, sin 180°, T_j = 150 °C, including body diode		2030	А			
Tj			-40 175	°C			

Absolute Maximum Ratings							
Symbol	Conditions	Values	Unit				
Module	Module						
I _{t(RMS)}		500	Α				
T _{stg}	module without TIM	-40 125	°C				
V _{isol}	AC sinus 50 Hz, t = 1 min	4000	٧				





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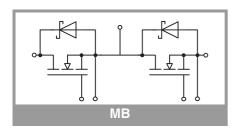
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Characteristics							
Symbol	Conditions	min.	typ.	max.	Unit		
MOSFET							
$V_{(BR)DSS}$	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ m/s}$	A, T _j = 25 °C	1700			V	
V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 57.7$	75 mA	1.6	2.8	4	V	
I _{DSS}	$V_{GS} = 0 \text{ V}, V_{DS} = 17$	′00 V, T _j = 25 °C			1.8	mA	
I _{GSS}	$V_{GS} = 22 \text{ V}, V_{DS} = 0$	V			700	nA	
R _{DS(on)}	V _{GS} = 18 V	T _j = 25 °C		8.1	10	mΩ	
	I _D = 161 A chiplevel	T _j = 150 °C		14		mΩ	
C _{iss}	$V_{GS} = 0 V$	T _j = 25 °C		27		nF	
Coss	$V_{DS} = 800 \text{ V}$	T _j = 25 °C		0.88		nF	
C _{rss}	f = 1 MHz	T _j = 25 °C		0.105		nF	
R _{Gint}	T _j = 25 °C			2.1		Ω	
Q_{G}	V _{DD} =1000V, V _{GS} =-	5 20V, I _D = 300 A		1470		nC	
t _{d(on)}	$V_{DD} = 900 \text{ V}$	T _j = 150 °C		64		ns	
t _r	$I_D = 300 \text{ A}$ $V_{GS} = -5 / +20 \text{ V}$	T _j = 150 °C		60		ns	
t _{d(off)}	$R_{Gon} = 0.7 \Omega$	T _j = 150 °C		162		ns	
t _f		T _j = 150 °C		32		ns	
Eon	$di/dt_{on} = 12 \text{ kA/}\mu\text{s}$	T _j = 150 °C		7.59		mJ	
E _{off}	$di/dt_{off} = 9.5 kA/μs$ $dv/dt_{off} = 22 kV/μs$	T _j = 150 °C		6.21		mJ	
R _{th(j-c)}	per MOSFET				0.065	K/W	
R _{th(c-s)}	per MOSFET (λ_{grea}	se=0.81 W/(m*K))		0.03		K/W	

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Inverse di	ode					
$V_F = V_{SD}$	I _F = 300 A	T _j = 25 °C		1.65	1.95	V
	chiplevel	T _j = 150 °C		2.51	2.86	V
V_{F0}	chiplevel	T _j = 25 °C		1.00	1.10	V
	Criipievei	T _j = 150 °C		0.86	0.96	V
r _F	chiplevel	T _j = 25 °C		2.2	2.8	mΩ
	Chibievei	T _j = 150 °C		5.5	6.3	mΩ
C _j	parallel to C_{oss} , $f = 1$ MHz, $V_R = 1700 \text{ V}$, $T_i = 25 ^{\circ}\text{C}$			1.026		nF
Q _c	$V_R = 800 \text{ V}, \text{ di/dt}_{\text{off}} = 500 \text{ A/}\mu\text{s},$ $T_j = 25 \text{ °C}$			0.95		μC
R _{th(j-c)}	per diode				0.056	K/W
R _{th(c-s)}	per diode (λ _{grease} =0	per diode (λ _{grease} =0.81 W/(m*K))		0.027		K/W





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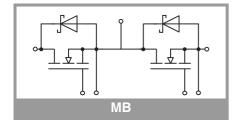
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Characteristics							
Symbol	Conditions	min.	typ.	max.	Unit		
Module							
L _{DS}			15			nΗ	
R _{DD'+SS'}	measured per	T _C = 25 °C	0.55			mΩ	
	switch	T _C = 125 °C		0.85		mΩ	
R _{th(c-s)1}	calculated without thermal coupling (λ _{grease} =0.81 W/(m*K))			0.008		K/W	
R _{th(c-s)2}	including thermal coupling, T _s underneath module (\(\lambda_{\text{grease}} = 0.81 \text{ W/(m*K)}\)			0.013		K/W	
Ms	to heat sink M6		3		5	Nm	
Mt		to terminals M6	2.5		5	Nm	
	1					Nm	
W		•			325	g	



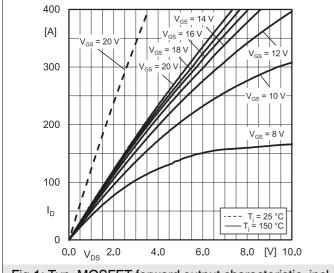


Fig.1: Typ. MOSFET forward output characteristic, incl. $R_{\text{DD}'+\,\text{SS}'}$

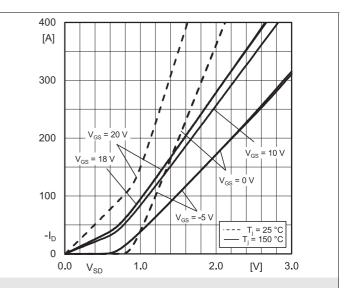


Fig. 2: Typ. reverse output characteristic, incl. R_{DD'+ SS'}

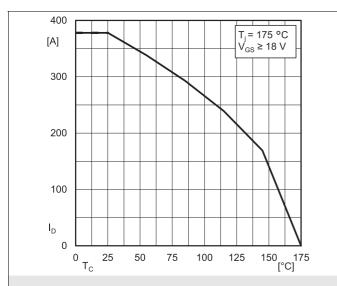


Fig. 3: Rated current vs. temperature $I_D = f(T_C)$

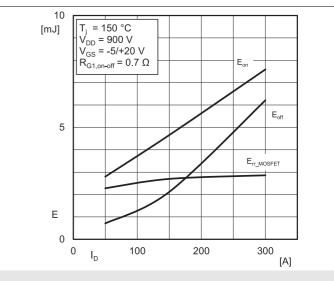


Fig. 4: Typ. switching energy $E = f(I_D)$ at R_{G1}

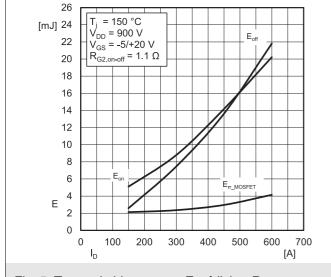


Fig. 5: Typ. switching energy $E = f(I_D)$ at R_{G2}

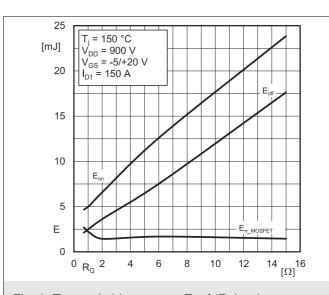


Fig. 6: Typ. switching energy $E = f(R_G)$ at I_{D1}

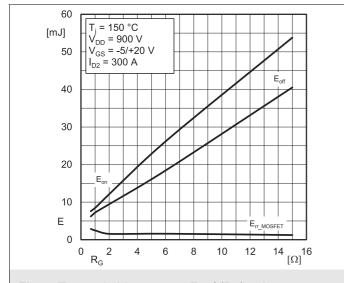


Fig. 7: Typ. switching energy $E = f(R_G)$ at I_{D2}

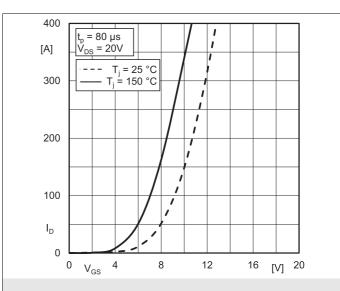


Fig. 8: Typ. MOSFET transfer characteristic

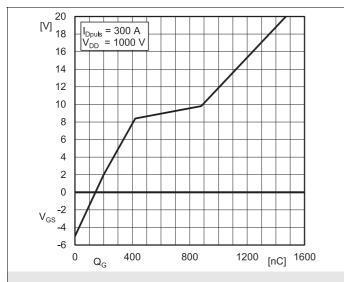


Fig. 9: Typ. gate charge characteristic

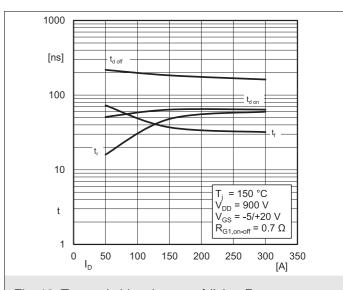


Fig. 10: Typ. switching times $t = f(I_D)$ at R_{G1}

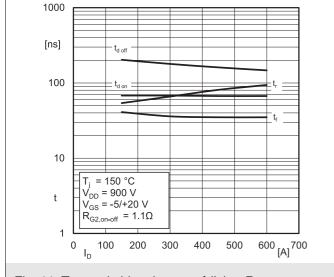


Fig. 11: Typ. switching times $t = f(I_D)$ at R_{G2}

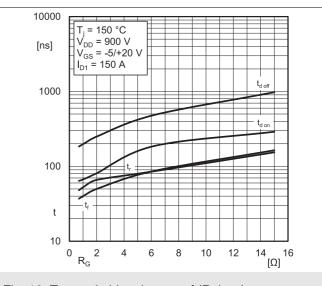
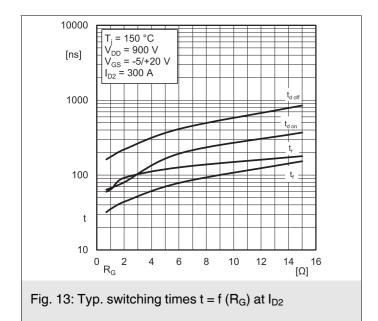
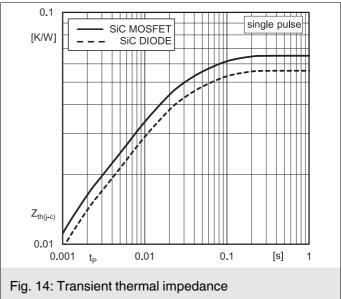
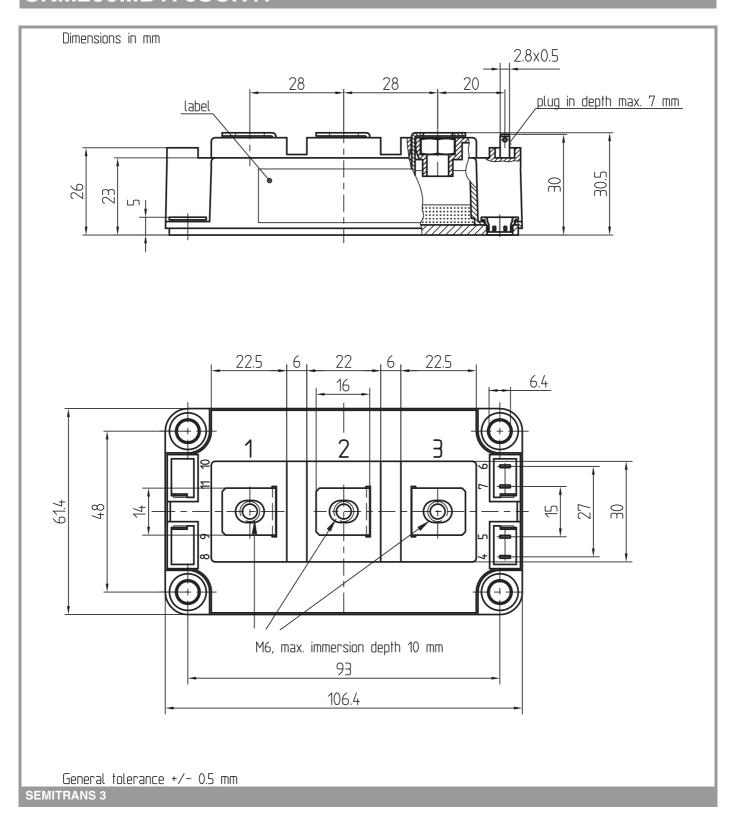
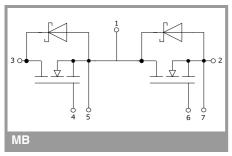


Fig. 12: Typ. switching times $t = f(R_G)$ at I_{D1}









This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

*IMPORTANT INFORMATION AND WARNINGS

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